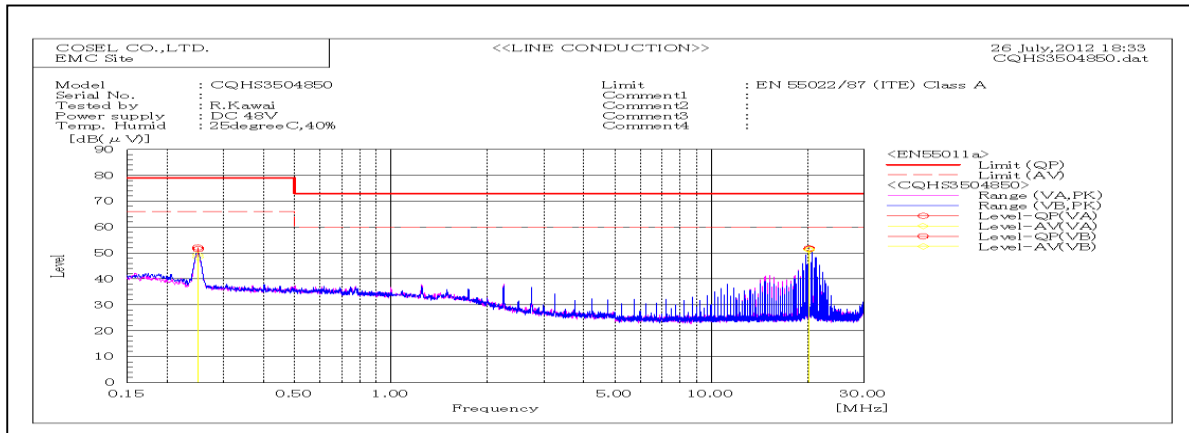
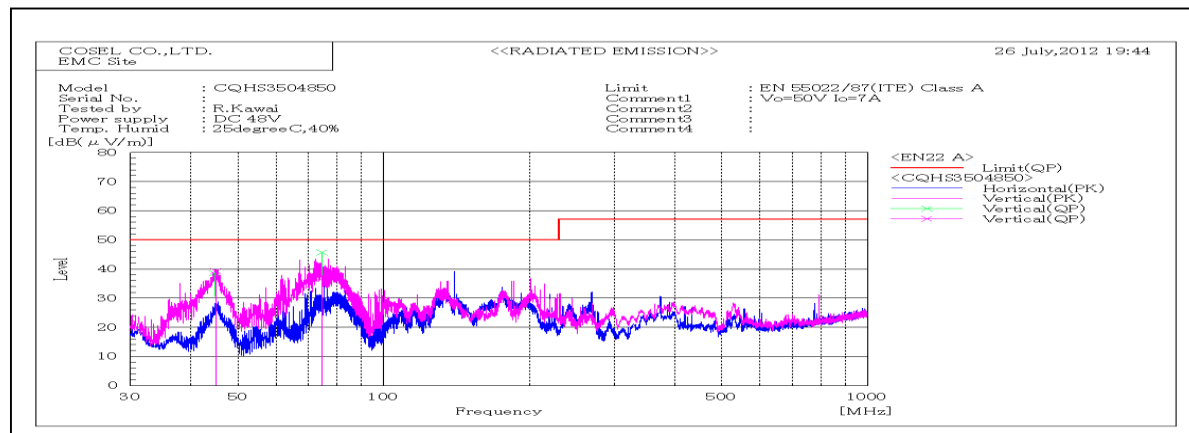


DATA SHEET		Date	26-Jul-12
Model	CQHS3504850	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai



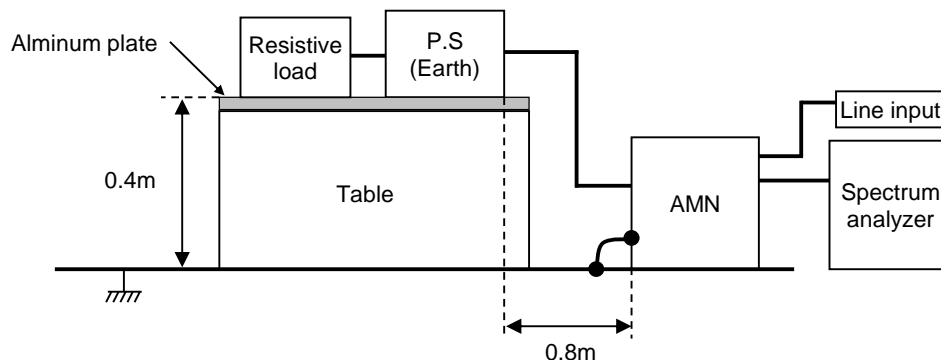
Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.24972		VA	31.5	28.4	20	51.5	48.4	79	66	27.5	17.6	Pass	
0.24875		VB	32	30.2	20.1	52.1	51.2	79	66	26.9	8.8	Pass	
20.2348		VB	30.9	29.2	20.9	51.8	49.3	73	60	21.2	16.7	Pass	
20.2367		VA	30.5	30.5	21	51.5	51.4	73	60	21.5	8.6	Pass	



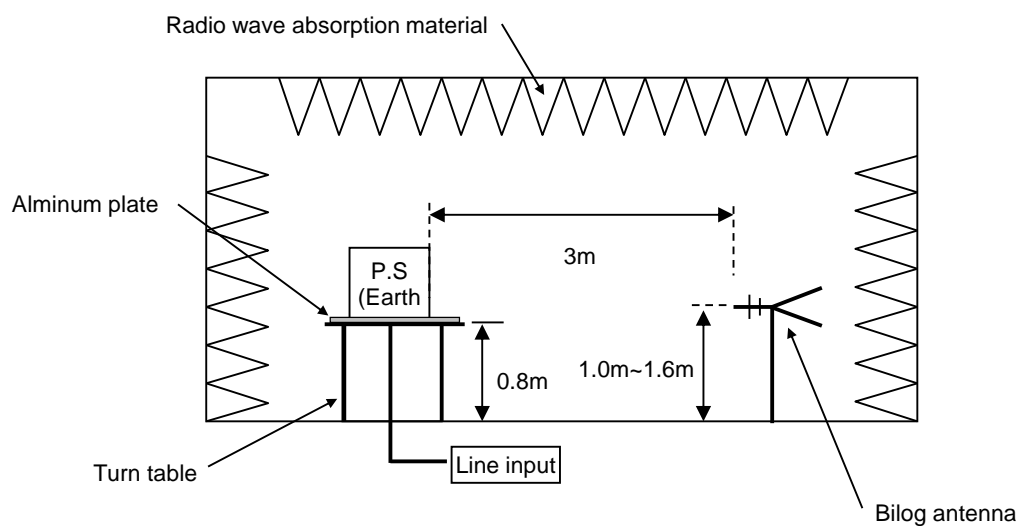
Frequency MHz	Polarization	Stability	Reading dB(μV)	Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/ Fail	Height cm	Angle deg	Remark
			QP		QP	QP					
44.958	H	Stable	58.9	-19.6	39.3	50	10.7	Pass	103	72	
74.612	H	Stable	57	-20.3	36.7	50	13.3	Pass	146	95	

DATA SHEET		Date	26-Jul-12
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	R.Kawai

### 1. Line conduction



### 2. Radiated emission

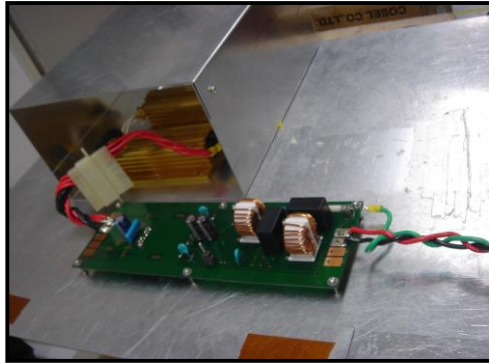


Test: EMI

Model Name: CQHS350 Series

○ Photographs of Test Set-Up

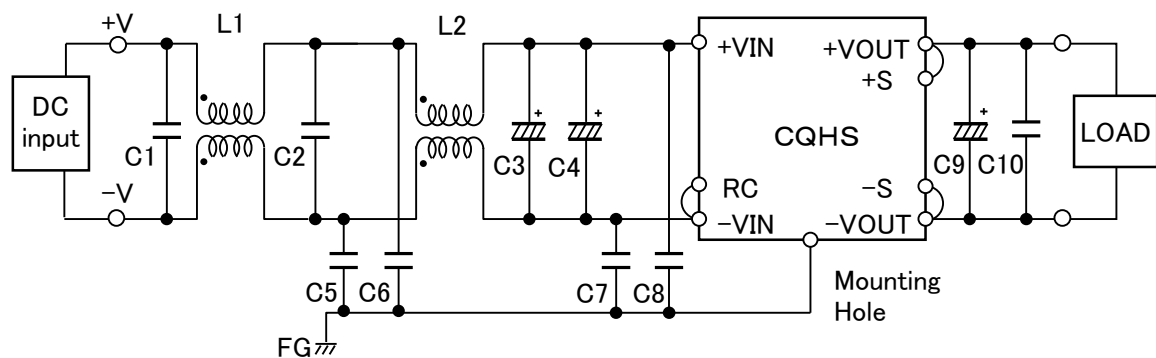
LINE CONDUCTION



RADIATED EMISSION



○ Test circuit



- L1, L2 : 0.5mH 15A Inductor (SC-15-05J NEC TOKIN)
- C1, C2 : 310V 2.2μ F Film capacitor (OKAYA ELEC)
- C3, C4 : 100V 68μ F Electlic capacitor (LXV NIPPON CHEMI-CON)
- C5, C6, C7, C8 : 250V 4700pF Ceramic capacitor (Type KY MURATA)
- C9 : CQHS3504832 50V 470μ F Electlic capacitor (LXZ NIPPON CHEMI-CON)
- C10 : CQHS3504850 80V 330μ F Electlic capacitor (KY NIPPON CHEMI-CON)
- C10 : 100V 0.1μ F Film capacitor (Nitsuko)